

## Supplementary Information for “Magnetotransport and magnetic properties of amorphous NdNi<sub>5</sub> thin films”

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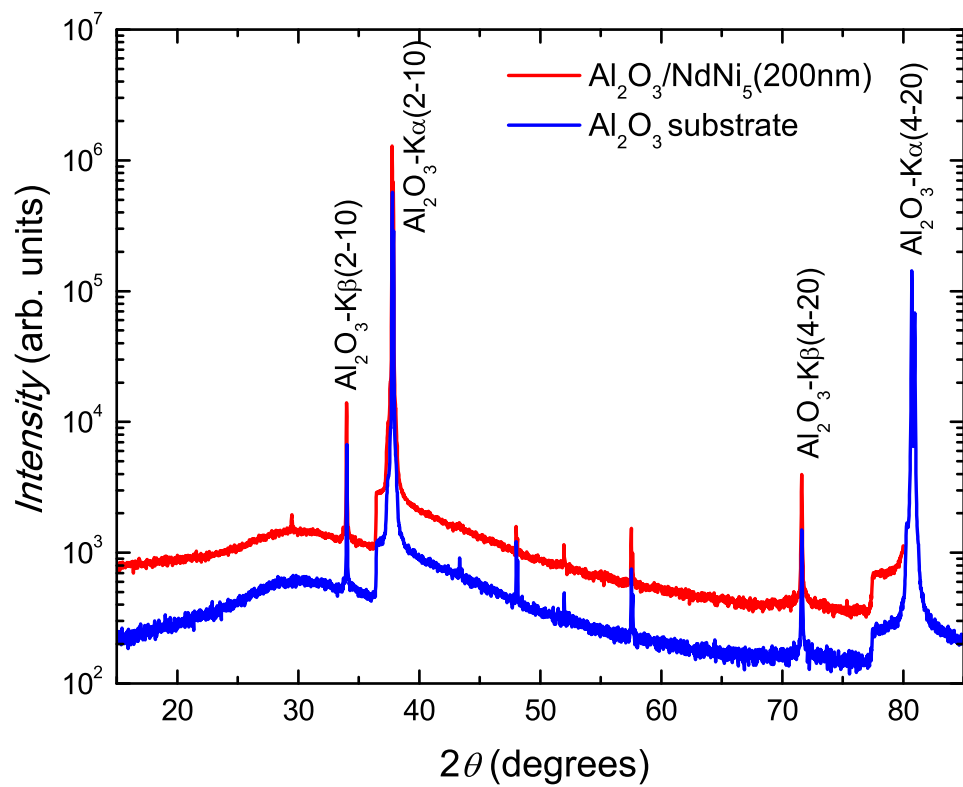


Fig. S1. **Structural characterization.** High-angle X-ray diffraction data from a 200-nm-thick NdNi<sub>5</sub> film deposited on Al<sub>2</sub>O<sub>3</sub>(1120) (red curve). The blue curve is the trace from the bare substrate.